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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/771,528	02/05/2004	Tetsu Kachi	248600US0	3061
22850	7590 02/09/2006		EXAM	INER
OBLON, SPIVAK, MCCLELLAND, MAIER & NEUSTADT, P.C.			SMITH, BRADLEY	
1940 DUKE ALEXANDR	STREET UA, VA 22314		ART UNIT	PAPER NUMBER
11221111121			2891	
			DATE MAILED: 02/09/2006	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)
	10/771,528	KACHI ET AL.
Office Action Summary	Examiner	Art Unit ,
	Bradley K. Smith	2891
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the c	orrespondence address
A SHORTENED STATUTORY PERIOD FOR REPL WHICHEVER IS LONGER, FROM THE MAILING D - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailin earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 136(a). In no event, however, may a reply be time will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE	. the mailing date of this communication. (35 U.S.C. § 133).
Status		
 1) ⊠ Responsive to communication(s) filed on 10 N 2a) ☐ This action is FINAL. 2b) ☑ This 3) ☐ Since this application is in condition for allowards closed in accordance with the practice under E 	s action is non-final. nce except for formal matters, pro	
Disposition of Claims		•
4) ☐ Claim(s) 1,2,4-6 and 8-16 is/are pending in the 4a) Of the above claim(s) is/are withdrays 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1,2,4-6 and 8-16 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or Application Papers	wn from consideration.	•
9)☐ The specification is objected to by the Examine	er.	
10)☐ The drawing(s) filed on is/are: a)☐ acc	epted or b) \square objected to by the E	Examiner.
Applicant may not request that any objection to the	drawing(s) be held in abeyance. See	e 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Ex		
Priority under 35 U.S.C. § 119		. •
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority document application from the International Bureau * See the attached detailed Office action for a list	s have been received. s have been received in Application rity documents have been receive u (PCT Rule 17.2(a)).	on No In this National Stage
Attachment(s) 1) X Notice of References Cited (PTO-892)	4) 🔲 Interview Summary	
 Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date <u>2/5/04</u>. 	Paper No(s)/Mail Da	te atent Application (PTO-152)

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DETAILED ACTION

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 1 and 2 are rejected under 35 U.S.C. 102(b) as being anticipated by Sony Corp (10-223901). Sony Corp. disclose a first layer composed of a group III nitride semiconductor, a second layer composed of a group III nitride semiconductor, and a gate electrode, wherein the first layer has a region formed between the gate electrode and the second layer; wherein a channel is formed in at least one of: (1) the first layer, (2) the second layer, (3) the region between the first layer and the second layer; and wherein the conductivity type of the second layer is inversed with respect to the conductivity type of carriers flowing in the channel (both holes and electrons could flow through the channel layer). With respect to claim 2, Sony Corp disclose an electrode in contact with the channel layer.

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Claims 1,2, 4-6, and 8-16 are rejected under 35 U.S.C. 102(e) as being anticipated by Saito et al. (US Patent 6,933,544). With respect to claims 1 and 16, Saito et al. disclose a first layer composed of a group III nitride semiconductor, a second layer composed of a group III nitride semiconductor, and a gate electrode, wherein the first layer has a region formed between the gate electrode and the second layer: wherein a channel is formed in at least one of: (1) the first layer, (2) the second layer. (3) the region between the first layer and the second layer; and wherein the conductivity type of the second layer is inversed with respect to the conductivity type of carriers flowing in the channel (both holes and electrons could flow through the channel layer). With respect to claim 2, Saito et al. disclose an electrode in contact with the channel layer. With respect to claims 4 and 15, Saito et al. disclose a first layer composed of a group III nitride semiconductor of a first conductivity type(1), a second layer (2) composed of a group III nitride semiconductor of a second conductivity type, a third layer (2) composed of a group III nitride semiconductor of the first conductivity type. and a gate electrode (6), wherein the first layer has a region formed between the gate electrode and the second layer; wherein the third layer has a region formed between the first layer and the second layer, and wherein the band gap of the third layer is less than the band gap of the first layer (figures 1,3,4, or 8 and column 12 lines 27-31 disclose that AlGaN could be substituted with InGaN). With respect to claim 5, Saito et al. disclose, a first layer composed of a group III nitride semiconductor of a first conductivity type, a second layer composed of a group III nitride semiconductor of a second conductivity type, a third layer composed of a group III nitride semiconductor, and a

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gate electrode, wherein the first layer has a region formed between the gate electrode and the second layer; wherein the third layer has a region formed between the first layer and the second layer, and wherein the band gap of the third layer is less than the band gap of the first layer and the second layer (the band gap could be changed by using a different material which Saito discloses in column 12 lines 27-31). With respect to claim 6, Saito disclose the third layer is composed of a group III nitride semiconductor. With respect to claim 8 Saito et al. disclose a gate electrode, a first layer composed of a group III nitride semiconductor of a first conductivity type, and a second layer composed of a group III nitride semiconductor of a second conductivity type located on a side of the first layer opposite to the gate electrode (see figure 1). With respect to claim 9-12 Saito disclose, the semiconductors are in direct contact and can have different bandgaps if different materials are used (the band gap could be changed by using a different material which Saito discloses in column 12 lines 27-31). With respect to claim 13, Saito et al. disclose the same structure therefore the device will operate the same (further more this is a device claim and the recitation does not further define the claimed invention, but just define how it operates). With respect to claim 14, Saito et al disclose a gate insulation layer between the first layer and the electrode (see figure 12).

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Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Bradley K. Smith whose telephone number is 571-272-1884. The examiner can normally be reached on 10-6.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Bill Baumeister can be reached on 571-272-1722. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free).

Bradley K Smith
Primary Examiner

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